



## Release Notes

### **NX System Release 13**

October, 2009

#### **Component Versions**

NX System Release 13 consists of the following component versions:

- NX Editor Version: 1.0.13.180
- NX Tester Firmware Version: 2.13.149

#### **Dependencies**

*It is strongly recommended that the upgrade be applied to the NX Testers and the NX Editor simultaneously*

#### **IMPORTANT NOTE:**

*Before updating your NX Testers to Release 13, please make sure that all programs are backed up.*

#### **New Features and Enhancements**

NX System Release 13 contains the following new features and enhancements:

- **Generic Spreadsheet Import:** The NX Editor supports importing connection and fixture data from an external spreadsheet that conforms to a specified format.
- **Probe Assisted Test Point Assignment:** This is a new method for assigning test points in the NX Editor. The user touches the point to be assigned with the NX Tester's probe, and the NX Editor automatically populates the corresponding data in the Fixture Blocks table. The NX Editor communicates with the NX Tester using the serial transfer cable.
- **Probe Assisted Assembly:** The probe function during a Test-Display workflow item has been enhanced to also include the connector-pin information of the other end of the connection. The tester resumes testing when the connection is made or if either the red or green button is pushed
- **Continuous Testing:** The Test-No Display workflow item has been enhanced to support continuous testing. This enables operators to flex a wire harness or cable assembly for a specific duration to test for intermittent open or short conditions. If an error is found during the specified duration, execution jumps to another cell in the workflow for error handling. The continuous testing mode is terminated by specifying a specific time interval, by specifying a specific number of test cycles, or by having the operator press the green button.
- **Immediate Miswire Display:** The Test-Display workflow item has been enhanced to allow for the selection of a new capability: Immediate Miswire Display. When selected, the NX Tester will immediately display a miswire condition.
- **Enhanced Early Exit Criteria:** The Test-Display workflow item has been enhanced to allow for either a short condition or early removal to trigger a jump to another workflow cell. Previously, these were mutually exclusive conditions for triggering early exit from the Test-Display workflow item.
- **Enhanced Report Capabilities:** The Report workflow item has been enhanced to provide additional flexibility for generating reports where there are multiple Test workflow items and/or multiple phases.



- **Hipot Fixture Diagnostics:** This has been added to the NX Hipot Tester's diagnostics menu. When selected, it causes the tester to execute a hipot test using the settings of the currently selected program. This is intended to be used on an empty fixture as a way of validating the fixture's suitability for hipot testing.
- **Enhanced Hipot IR Testing:** The Hipot Insulation Resistance testing range has been extended to 1500 MOhms

## Bug Fixes and Improvements

NX System Release 13 provides the following improvements and includes fixes for the following problems:

- Repeating sounds in the Test-Display workflow item are now functional.
- If a short error is encountered during testing, once all errors have been resolved, a re-test is automatically executed. This ensures that the short error was not resolved by removing the shorted connection from the fixture. Previous firmware versions would re-test only if short errors were present after all connections were satisfied.
- An open detection switch is now indicated by displaying "SWITCH OPEN" on the first line and the detection switch name on the second line.
- In the PROBE mode, an up-arrow is displayed in the upper right corner preceding the C (^C), if more than one point is connected to the probed point. This is intended to prompt the user to use the up-arrow button to scroll through all the points connected to the probed point.
- Kelvin testing speed has been improved.
- After a hipot test, the Report workflow item will now show hipot IR values.
- The Dielectric Withstand test has a new error: DW-CURRENT. This indicates that the error condition may be caused by insufficient current or voltage settings.
- Improved startup diagnostics for NX Hipot Testers.
- The power up sequence for the NX Pro+ Tester has been improved. If the tester is powered up before the expansion units, the test program will no longer display an error message.